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Microscopy AND Microanalysis



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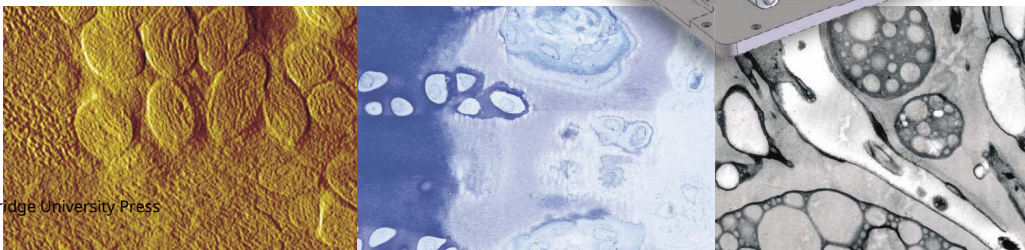
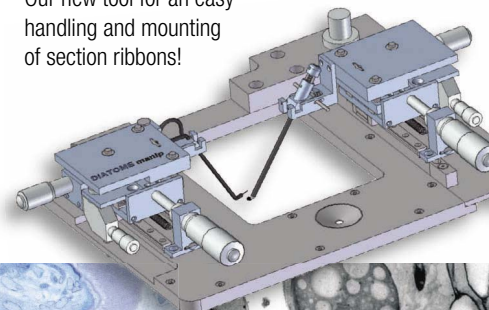
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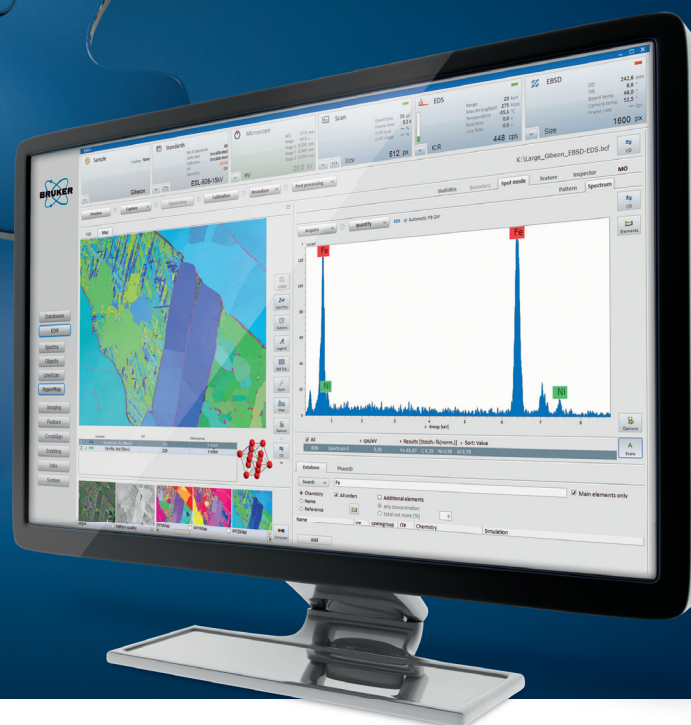
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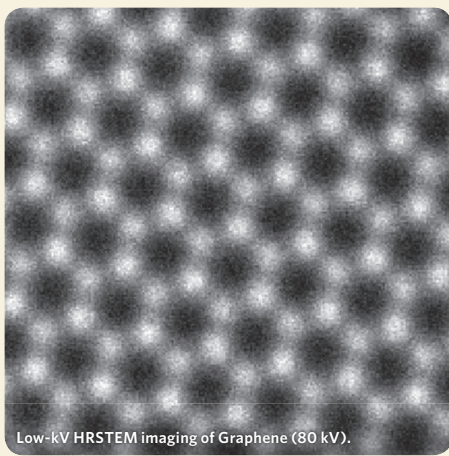
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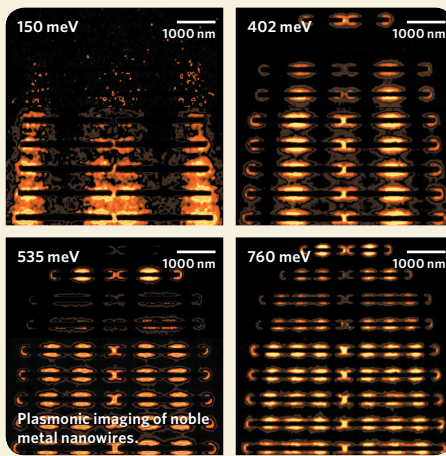
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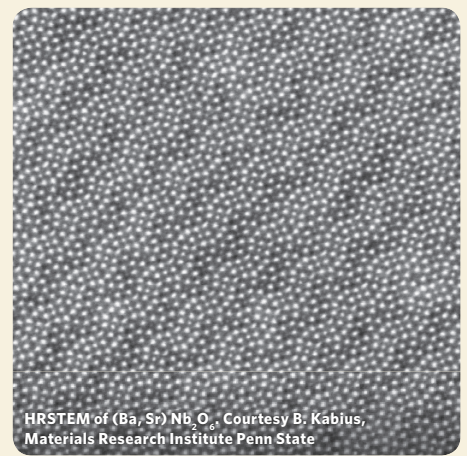
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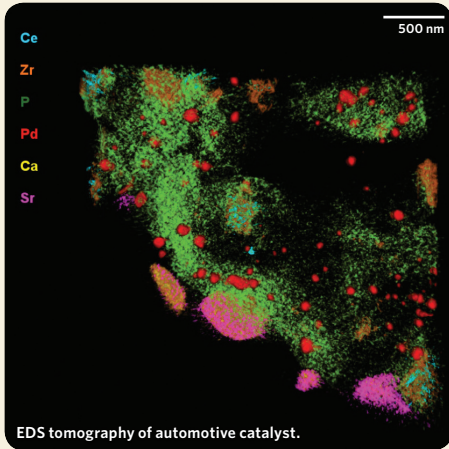
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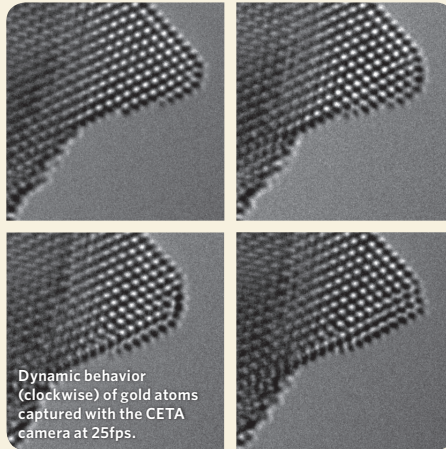
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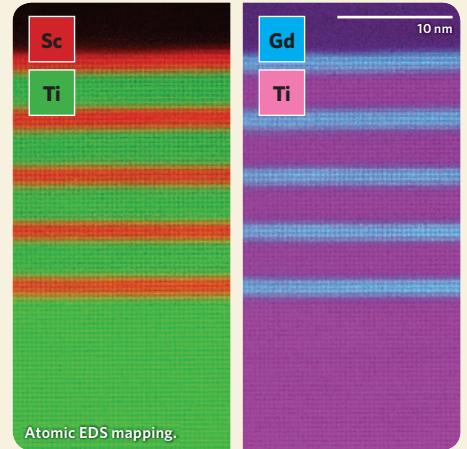
HRSTEM of (Ba, Sr) Nb₂O₆. Courtesy B. Kabius, Materials Research Institute Penn State



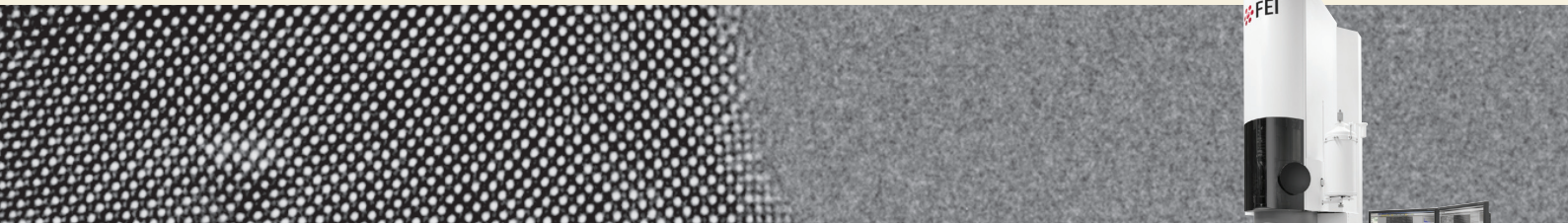
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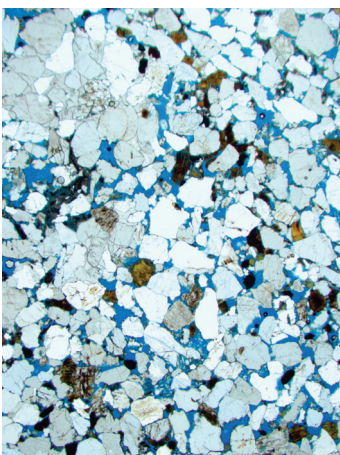
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Introducing the EMS

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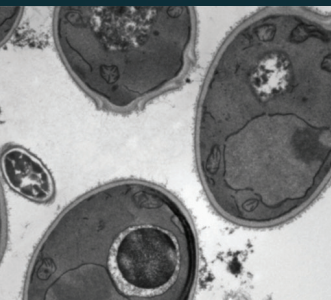
the solution for Evaporation-Controlled Automated Embedding and Polymerization

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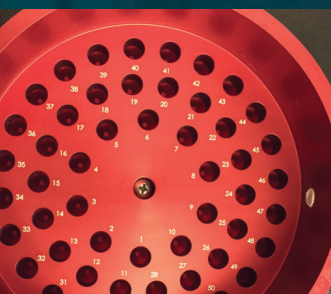
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As a practical approach the instrument can be loaded by the end of a workday and (when using acetone or propylene oxide) by the next morning the vials are ready for polymerization after the vials have been topped up with pure resin.

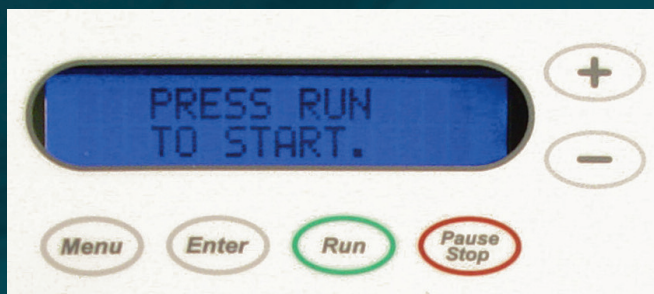
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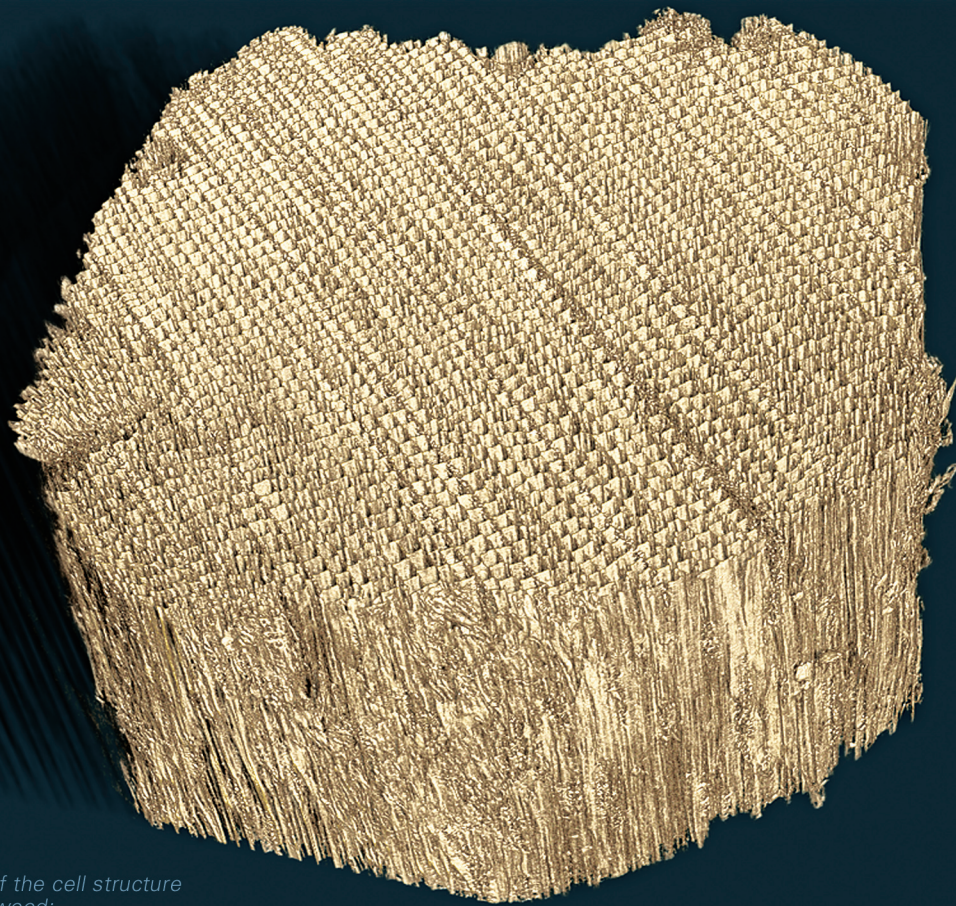
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MATERIALS APPLICATIONS

- Quantitative Electron-Excited X-Ray Microanalysis of Borides, Carbides, Nitrides, Oxides, and Fluorides with Scanning Electron Microscopy/Silicon Drift Detector Energy-Dispersive Spectrometry (SEM/SDD-EDS) and NIST DTSA-II 1327
Dale E. Newbury and Nicholas W. M. Ritchie
- Numerous Iron-Rich Particles Lie on the Surface of Erionite Fibers from Rome (Oregon, USA) and Karlik (Cappadocia, Turkey) 1341
Alessandro Croce, Mario Allegrina, Caterina Rinaudo, Giovanni Gaudino, Haining Yang, and Michele Carbone
- Interferometric Diffraction from Amorphous Double Films 1348
Aram Rezikyan, James A. Belcourt, and Michael M. J. Treacy
- μ CT-Based Analysis of the Solid Phase in Foams: Cell Wall Corrugation and other Microscopic Features 1361
Samuel Pardo-Alonso, Eusebio Solórzano, Jerome Vicente, Loes Brabant, Manuel L. Dierick, Ingo Manke, Andr Hilger, Ester Laguna, and Miguel Angel Rodriguez-Perez

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*Volume rendering of the cell structure
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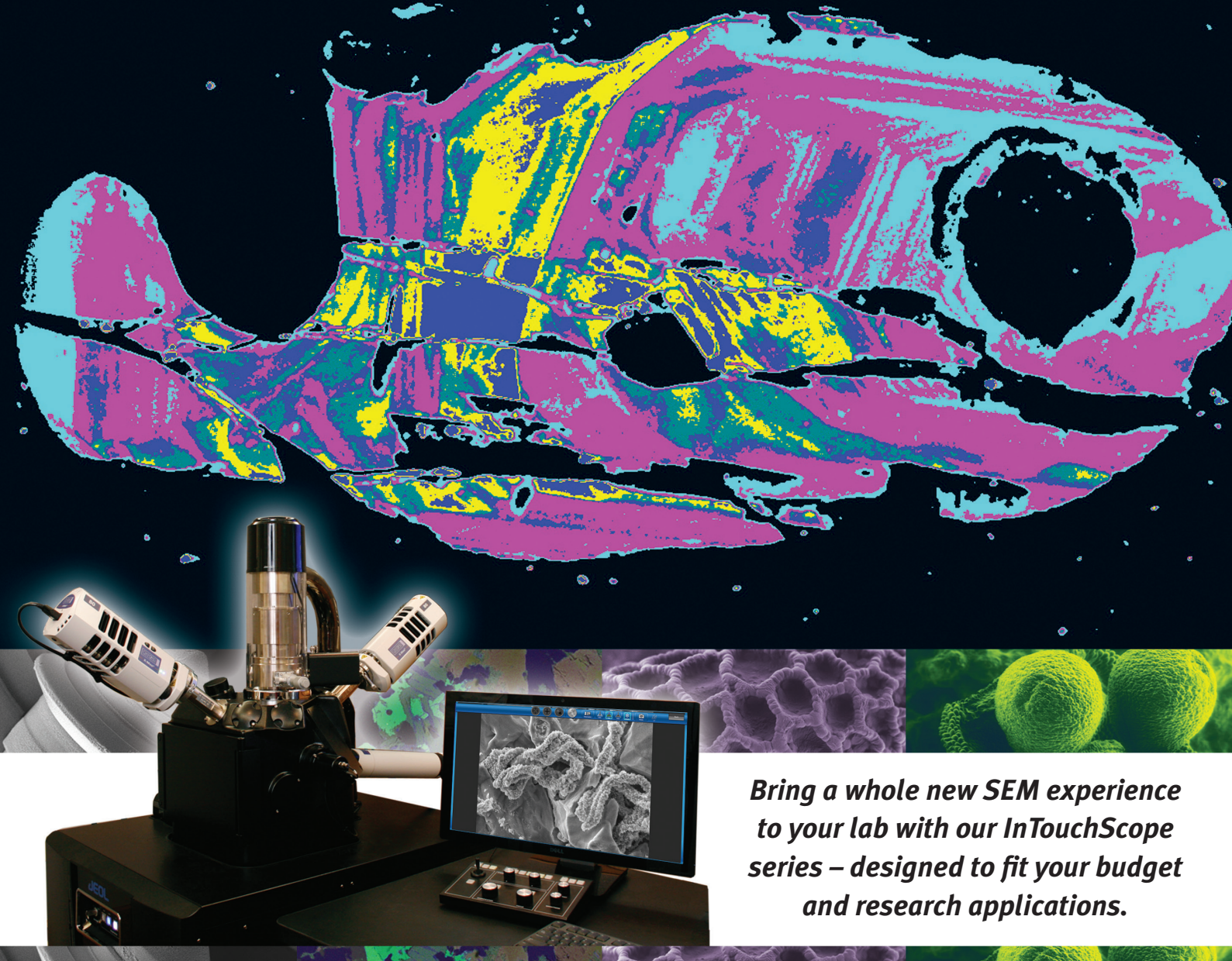
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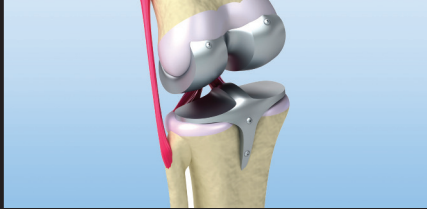
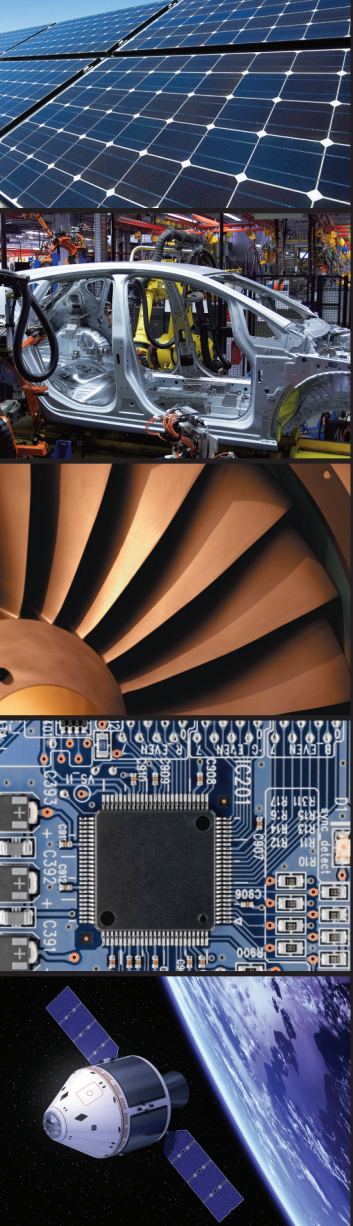
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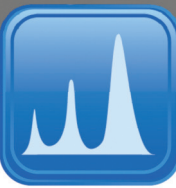
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